

Claims

1. A gas discharge display panel comprising a substrate, a dielectric layer, and a protective layer, the dielectric layer and the protective layer being formed in the stated order on a surface of the substrate, wherein

the protective layer contains H in a range of 300 mass ppm to 10000 mass ppm inclusive with respect to a MgO content of the protective layer.

2. The gas discharge display panel of Claim 1, wherein the H content of the protective layer is in a range of less than 1500 mass ppm with respect to the MgO content.

3. The gas discharge display panel of Claim 1, wherein the protective layer further contains Si in a range of 20 mass ppm to 5000 mass ppm inclusive with respect to the MgO content.

4. The gas discharge display panel of Claim 1, wherein the protective layer further contains Ge in a range of 10 mass ppm or above and below 500 mass ppm with respect to the MgO content.

5. A gas discharge display panel comprising a substrate, a dielectric layer, and a protective layer, the dielectric layer and the protective layer being formed in the stated order on a surface of the substrate, wherein

when the protective layer is subjected to a cathodoluminescence spectroscopy, a relative area intensity of a first intensity with

respect to a second intensity for a light emission peak area is in a range of 0.6 to 1.5 inclusive, where the first intensity is a light emission peak intensity generated in a wavelength range of 720nm or above and below 770nm and the second intensity is a light emission peak intensity generated in a wavelength range of 300nm or above and below 450nm.

6. The gas discharge display panel of Claim 5, wherein the protective layer contains H in addition to MgO.

7. The gas discharge display panel of Claim 5, wherein the protective layer contains H and Si in addition to MgO, where the Si content is in a range of 20 mass ppm to 5000 mass ppm inclusive with respect to the MgO content.

8. A gas discharge display panel comprising a substrate, a dielectric layer, and a protective layer, the dielectric layer and the protective layer being formed in the stated order on a surface of the substrate, wherein

when the protective layer is subjected to a cathodoluminescence spectroscopy, a relative area intensity of a second intensity with respect to a third intensity for a light emission peak area is in a range of 0.9 or above, where the second intensity is a light emission peak intensity generated in a wavelength range of 450nm or above and below 600nm and the third intensity is a light emission peak intensity generated in a wavelength range of 300nm or above and below 450nm.

9. The gas discharge display panel of Claim 8, wherein the protective layer contains H in addition to MgO.

10. The gas discharge display panel of Claim 8, wherein
5 the protective layer contains H and Ge in addition MgO, where the Ge content is in a range of 10 mass ppm to 300 mass ppm inclusive with respect to the MgO content.

11. The gas discharge display panel of Claim 7, wherein
10 the protective layer contains Ge in a range of 10 mass ppm or above and below 300 mass ppm with respect to the MgO content.